

**July 2010** 

# FDFME3N311ZT

# Integrated N-Channel PowerTrench® MOSFET and Schottky Diode 30 V, 1.8 A, 299 m $\Omega$

#### **Features**

- Max  $r_{DS(on)}$  = 299 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 1.6 A
- Max  $r_{DS(on)}$  = 410 m $\Omega$  at  $V_{GS}$  = 2.5 V,  $I_D$  = 1.3 A
- Low profile: 0.55 mm maximum in the new package MicroFET 1.6x1.6 **Thin**
- Free from halogenated compounds and antimony oxides
- HBM ESD protection level > 1600 V (Note 3)
- RoHS Compliant



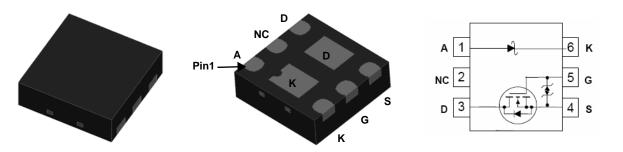
### **General Description**

This device is designed specifically as a single package solution for a boost topology in cellular handset and other ultra-portable applications. It features a MOSFET with low input capacitance, total gate charge and on-state resistance. An independently connected schottky diode with low forward voltage and reverse leakage current to maximize boost efficiency.

The MicroFET 1.6x1.6 **Thin** package offers exceptional thermal performance for it's physical size and is well suited to switching and linear mode applications.

### **Application**

■ Boost Functions



BOTTOM MicroFET 1.6x1.6 Thin

# MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Parameter			
$V_{DS}$	Drain to Source Voltage			30	V
$V_{GS}$	Gate to Source Voltage			±12	V
	Drain Current -Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	1.8	Α
ID	-Pulsed		4.5	_ A	
D	Power Dissipation for Single Operation	T <sub>A</sub> = 25 °C	(Note 1a)	1.4	W
$P_{D}$	Power Dissipation for Single Operation $T_A = 25 ^{\circ}\text{C}$ (Note 1b)			0.6	VV
$V_{RRM}$	Schottky Repetitive Peak Reverse Voltage			28	V
Io	Schottky Average Forward Current			1	Α
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature	Range	(Note 4)	-55 to +150	°C

#### **Thermal Characteristics**

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$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1a)	90	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1b)	195	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1c)	110	*C/VV
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Single Operation)	(Note 1d)	234	

#### **Package Marking and Ordering Information**

	Device Marking	Device	Package	Reel Size	Tape Width	Quantity
Ī	1T	FDFME3N311ZT	MicroFET 1.6x1.6 Thin	7"	8mm	5000 units

# **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		25		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			1	μΑ
$I_{GSS}$	Gate to Source Leakage Current	$V_{GS} = \pm 12 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

#### **On Characteristics**

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	0.5	1	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		-3		mV/°C
		$V_{GS} = 4.5 \text{ V}, I_D = 1.6 \text{ A}$		235	299	
r <sub>DS(on)</sub>	r <sub>DS(on)</sub> Drain to Source On Resistance	$V_{GS} = 2.5 \text{ V}, I_D = 1.3 \text{ A}$		296	410	mΩ
	$V_{GS} = 4.5 \text{ V}, I_D = 1.6 \text{ A}, T_J = 125 \text{ °C}$		365	603		
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 1.6 A		2.8		S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 45 V V 6 V	55	75	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	15	20	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 101112	7	10	pF
$R_g$	Gate Resistance		7.5		Ω

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	V 45 V 1 4 0 A	6	12	ns
t <sub>r</sub>	Rise Time	$V_{DD}$ = 15 V, $I_{D}$ = 1.6 A, $V_{GS}$ = 4.5 V, $R_{GEN}$ = 6 Ω	8	16	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = 4.5 V, R <sub>GEN</sub> = 0.12	22	35	ns
t <sub>f</sub>	Fall Time		1.4	10	ns
$Q_g$	Total Gate Charge	V 45 V V 45 V	1	1.4	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{GS} = 4.5 \text{ V}, V_{DD} = 15 \text{ V},$ $I_{D} = 1.6 \text{ A}$	0.2		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	10 - 1.57	0.3		nC

#### **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 0.9 \text{ A}$ (Note 2)		0.9	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	L = 1 6 A di/dt = 100 A/us		12	22	ns
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = 1.6 A, di/dt = 100 A/μs		3.1	10	nC

# **Schottky Diode Characteristics**

ı	Reverse Leakage	V - 29 V	T <sub>J</sub> = 25 °C	15	100	μА
¹R	Reverse Leakage	$V_{R} = 28 \text{ V}$	T <sub>J</sub> = 85 °C	0.46	4.7	mA
V_	Forward Voltage	I <sub>E</sub> = 1 A	T <sub>J</sub> = 25 °C	0.47	0.57	\/
٧F	V <sub>F</sub> Forward Voltage	IF = I A	T <sub>J</sub> = 85 °C	0.45		V
V	Forward Voltage	I <sub>E</sub> = 500 mA	T <sub>J</sub> = 25 °C	0.38	0.48	\/
٧F	V <sub>F</sub> Forward Voltage	IF = 500 IIIA	T <sub>J</sub> = 85 °C	0.33		V

#### **Electrical Characteristics**

#### Notes:

- 1. R<sub>0,1A</sub> is determined with the device mounted on a 1 in<sup>2</sup> oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0,1C</sub> is guaranteed by design while R<sub>0,1A</sub> is determined by the user's board design.
  - (a) MOSFET  $R_{\theta JA}$  = 90 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB.
  - (b) MOSFET  $R_{\theta JA}$  = 195 °C/W when mounted on a minimum pad of 2 oz copper.
  - (c) Schottky  $R_{\theta JA}$  = 110 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper, 1.5 " x 1.5 " x 0.062" thick PCB.
  - (d) Schottky  $R_{\theta,IA}$  = 234 °C/W when mounted on a minimum pad of 2 oz copper.



a. 90 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 195 °C/W when mounted on a minimum pad of 2 oz copper.



c. 110 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



d. 234 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.
- 4. Rating is applicable to MOSFET only.

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

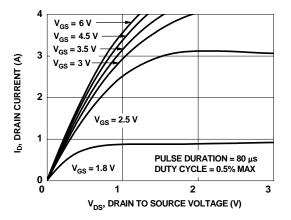


Figure 1. On Region Characteristics

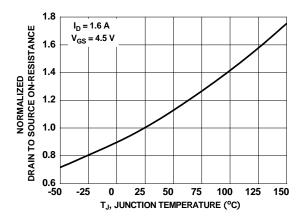


Figure 3. Normalized On Resistance vs Junction Temperature

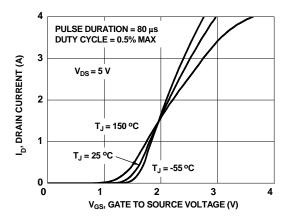


Figure 5. Transfer Characteristics

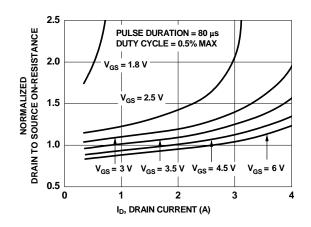


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

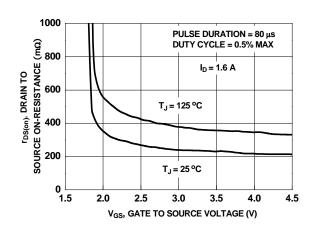


Figure 4. On-Resistance vs Gate to Source Voltage

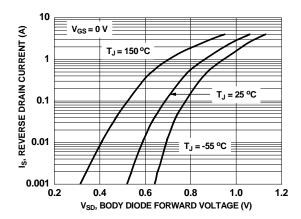


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

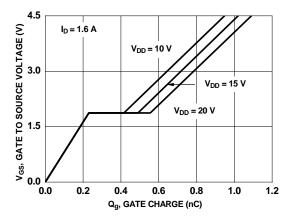


Figure 7. Gate Charge Characteristics

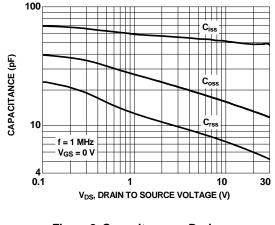


Figure 8. Capacitance vs Drain to Source Voltage

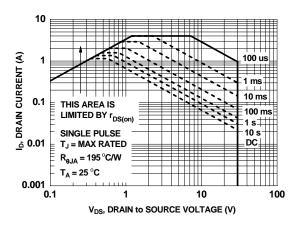


Figure 9. Forward Bias Safe Operating Area

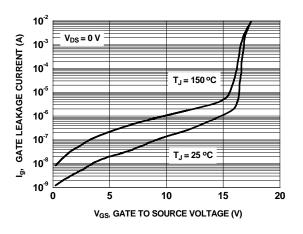


Figure 10. Gate Leakage Current vs Gate to Source Voltage

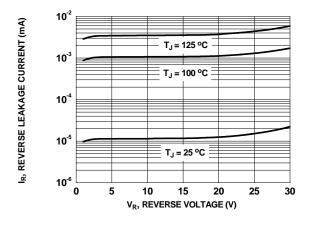


Figure 11. Schottky Diode Reverse Current

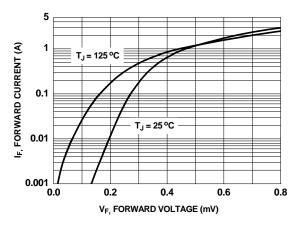


Figure 12. Schottky Diode Forward Voltage

# **Typical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted

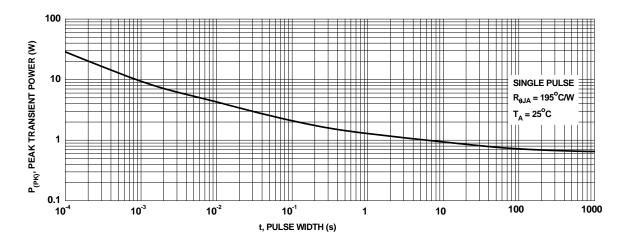


Figure 13. Single Pulse Maximum Power Dissipation

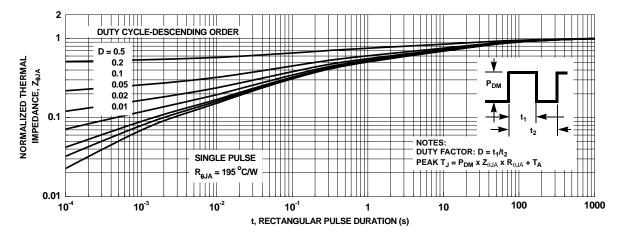
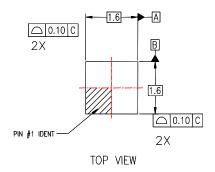
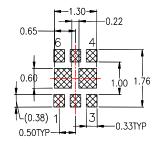


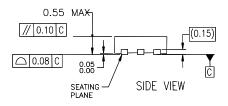
Figure 14. Junction-to-Ambient Transient Thermal Response Curve

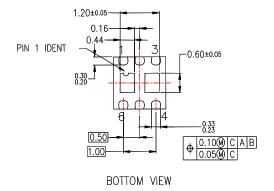
# **Dimensional Outline and Pad Layout**





RECOMMENDED LAND PATTERN









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